Experimental studies and multiscale modeling of latent tracks in radiation-resistant insulators

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SHI track: temporal and spatial scales



Too fast, too small, too large excitation levels

Can not be described with macroscopic models

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Multiscale microscopic model of track excitation





Σ

2. A model of electron-lattice coupling and lattice excitation (10⁻¹² s) Spatial and temporal distributions of energy and momenta transferred into the lattice

3. MD of lattice relaxation (10⁻

⁹ S)

Structure transformations

R.A. Rymzhanov et al., J.PhysD .Appl.Phys. 50 (2017) 475301

Monte Carlo (TREKIS) of the initial electronic kinetics

Time-Resolved Electron Kinetics in SHI Irradiated Solids N.A.Medvedev et al., J. Phys. D Appl. Phys. 48 (2015) 355303

$$t = 10^{-17} \text{ s} - 10^{-14} \text{ s}$$

Event by event simulations

Scattering on spatially and dynamically coupled particles

$$\frac{\partial^2 \sigma}{\partial \Omega \partial(\mathbf{h}\omega)} \sim \left| V(\mathbf{k}) \right|^2 \operatorname{Im}\left(\frac{-1}{\varepsilon(k,\omega)}\right)$$



- SHI passage and generation of fast primary δ-electrons

 Š^{10⁻¹⁷} s
 Špreading of δ-electrons and secondary electron cascading. Creation of secondary electrons and holes
 Kinetics of all next generations of electrons and holes
 Kinetics of deep shell holes ~10⁻¹⁵ s
- **5.** Radiation decay and photons transport

Complex Dielectric Function

e.g. Ritchie and Howie formalism

individual scattering: ionization of the valence band or deep shells
collective scattering: plasmons, phonons etc.

$$\frac{\partial^2 \sigma_{el}}{\partial k \partial (\mathbf{h}\omega)} \sim \operatorname{Im} \left[\frac{-1}{\varepsilon(\omega, q)} \right] = \sum_{i=1}^{n^{os}} \frac{A_i \gamma_i \mathbf{h}\omega}{\left[\mathbf{h}^2 \omega^2 - \left(E_{0i} + \mathbf{h}^2 q^2 / (2m_e)\right)^2\right]^2 + \left(\gamma_i \mathbf{h}\omega\right)^2}$$



N.A.Medvedev et al., J. Phys. D Appl. Phys. 48 (2015) 355303

TREKIS: Verification of model Electronic energy loss of ions and inelastic mean free paths of



MC TREKIS + MD LAMMPS



MD code LAMMPS Plimpton S. J. Comput. Phys. 117 (1995) 1–19

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Threshold and morphology of tracks in Al₂O₃



167 Mev Xe Crystalline damaged discontinuous track of 1.8 nm diameter after 50 fs

Residual strain of Xe 167 MeV track in Al₂O₃

Lattice deformation:

Radial density of Al₂O₃

Simulations



Experiment





underdense core is surrounded by overdense shell

O'Connell et al NIMB 374 (2015) 97

Recrystallization of tracks in different dielectrics



MgO - only point defects were created
 Al₂O₃ - crystalline discontinuous track of D ~ 2 nm
 YAG - continuous amorphous track of D ~ 6.5 nm

R.A. Rymzhanov et al., Scientific Reports 9 (2019) 3837

Recrystallization plays a crucial role for track formation in MgO, $\rm Al_2O_3$ and YAG



R.A. Rvmzhanov et al., Scientific Reports 9 (2019) 3837

Overlapping of SHI tracks.

Bi 700 MeV in Al₂O₃

- Second ion causes annealing of defects created by the first one
- Ions at longer distances cause partial annealing of older tracks

 Radius of recovery is ~ 6.5 nm (experimental ~ 5.4 nm) corresponding to the track density of ~ 2.7×10¹² CM⁻²



R.A. Rymzhanov, et.al, NIMB 435 (2018), 121-125

Recrystallization during track formation propcess



MgO - only point defects were created around the ion trajectory
 Al₂O₃ - crystalline discontinuous track with the diameter about 2 nm
 YAG - continuous amorphous track of ~6.5 nm in diameter

p-Si₃N₄ + Xe 220 МэВ



Si3N4 +Bi, 700 MeV



$a-Si_3N_4 + Bi 710 M_2B, 5x10^{10} cm^{-2}$



Surface effects of dense ionization in ceramics and oxides

167 MeV Xenon ion induced hillocks in TiO₂

Surface effects of dense ionization in ceramics and oxides

Xe (220 MeV) + TiO₂: Hillock size vs irradiation temperature

Amorphous hillocks in YAG

YAG demonstrates almost no damage recovery: amorphous cylindrical track and amorphous hillock

R.A. Rymzhanov et al., J.App.Phys. 2020, 127(1) 015901

Thank you for your attention!